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LIST OF REFERENCES CITED BY APPLICANT TAMATSUKA										
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N	АМ	OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) Abstract of Japanese Patent Publication No. 11195565A; dated July 21, 1999								
	AN	"Dynamic Behavior of Intrinsic Point Defects in FZ and CZ Silicon Crystals," Mat. Res. Soc. Symp. Proc. Vol. 262, 1992 Materials Research Society, ABE et al., pp. 3-13								
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*EXAMINER: